



# FQB34N20 / FQI34N20

### 200V N-Channel MOSFET

#### **General Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

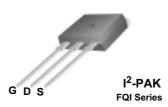
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supply, DC-AC converters for uninterrupted power supply, motor control.

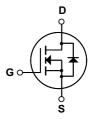
#### **Features**

- 31A, 200V,  $R_{DS(on)}$  = 0.075 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 60 nC)
- Low Crss (typical 55 pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- · RoHS Compliant









### **Absolute Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		FQB34N20 / FQI34N20	Units
V <sub>DSS</sub>	Drain-Source Voltage		200	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C) - Continuous (T <sub>C</sub> = 100°C)		31	Α
			20	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	124	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	640	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	31	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	18	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		5.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> = 25°C) *		3.13	W
	Power Dissipation (T <sub>C</sub> = 25°C)		180	W
	- Derate above 25°C		1.43	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

### **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.7	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Cha	aracteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		200			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C			0.2		V/°C
I <sub>DSS</sub>	7 0 1 1/1 5 1 0 1	V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V				1	μΑ
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 160 V, T <sub>C</sub> = 125°C				10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V				100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V				-100	nA
On Cha	racteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 15.5 A			0.06	0.075	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 15.5 A	(Note 4)		25		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0  MHz			2400 430 55	3100 560 70	pF pF pF
	ing Characteristics				- 55	70	Рι
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 100 V, I <sub>D</sub> = 34 A,			40	90	ns
t <sub>r</sub>	Turn-On Rise Time	$R_{\rm G} = 25 \ \Omega$			280	570	ns
$t_{d(off)}$	Turn-Off Delay Time				125	260	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4, 5)		115	240	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 160 V, I <sub>D</sub> = 34 A,			60	78	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V			17		nC
Q <sub>gd</sub>	Gate-Drain Charge		(Note 4, 5)		27		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings	S				
I <sub>S</sub>	Maximum Continuous Drain-Source Dic	ode Forward Current				31	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F					124	Α
\ /	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 31 A				1.5	V
$V_{SD}$							
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 34 \text{ A},$			150		ns

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 1.0mH, I<sub>AS</sub> = 31A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  34A, di/dt  $\leq$  300A/μs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300μs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

### **Typical Characteristics**

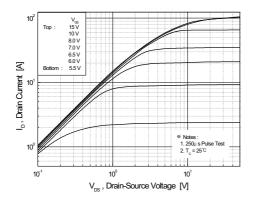


Figure 1. On-Region Characteristics

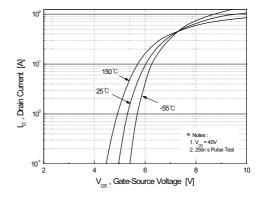


Figure 2. Transfer Characteristics

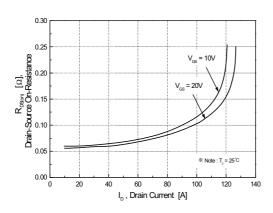


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

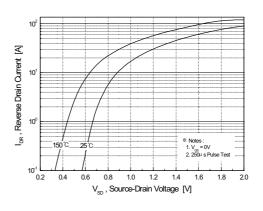


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

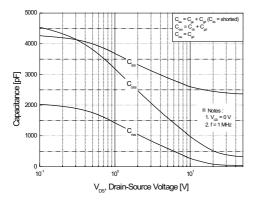


Figure 5. Capacitance Characteristics

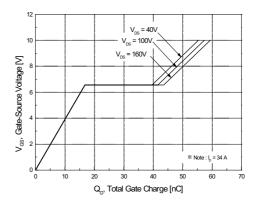


Figure 6. Gate Charge Characteristics

### Typical Characteristics (Continued)

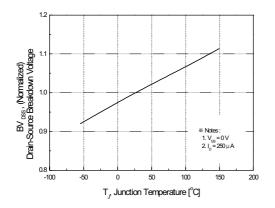
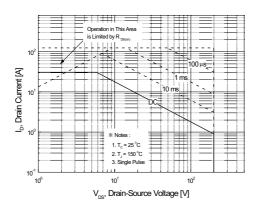


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



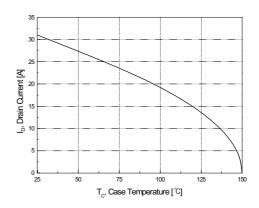


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

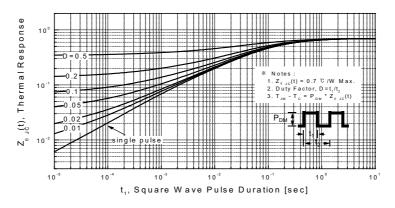
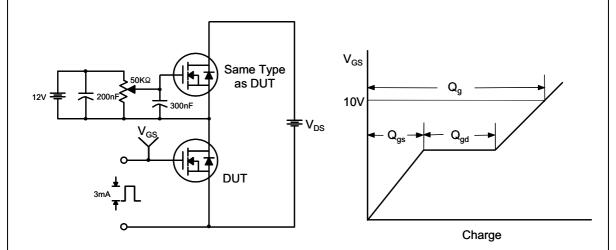
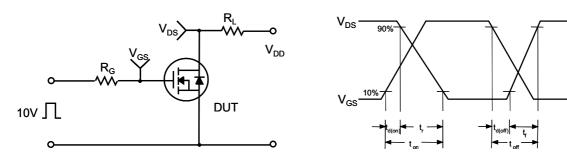


Figure 11. Transient Thermal Response Curve

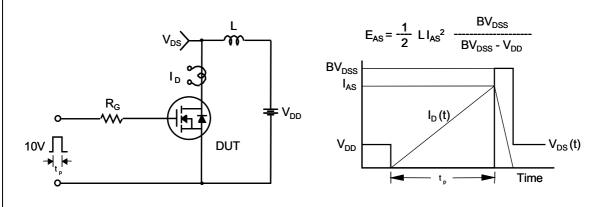
### **Gate Charge Test Circuit & Waveform**



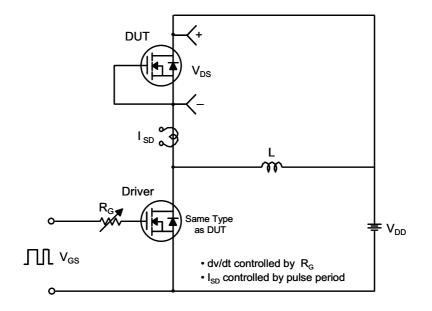
### **Resistive Switching Test Circuit & Waveforms**

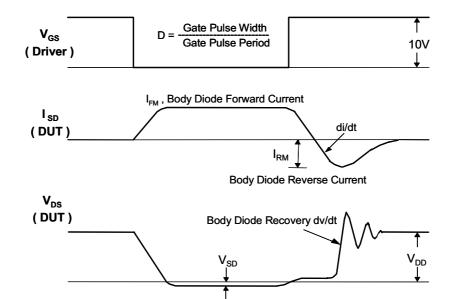


#### **Unclamped Inductive Switching Test Circuit & Waveforms**



#### Peak Diode Recovery dv/dt Test Circuit & Waveforms

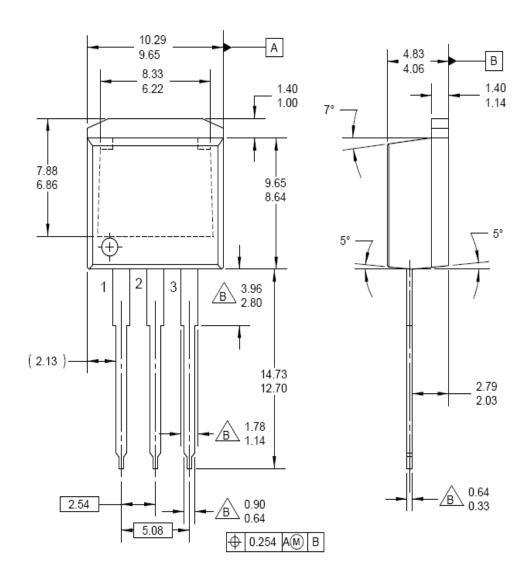




Body Diode Forward Voltage Drop

### **Mechanical Dimensions**

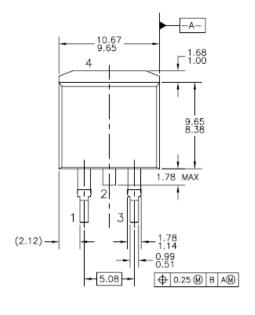
# I<sup>2</sup> - PAK

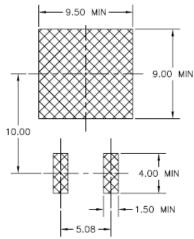


Dimensions in Millimeters

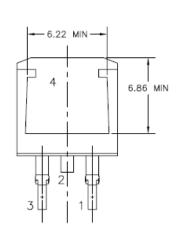
### **Mechanical Dimensions**

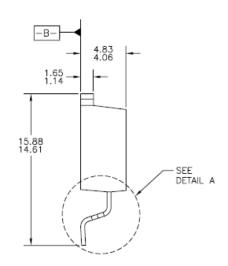
D<sup>2</sup> - PAK

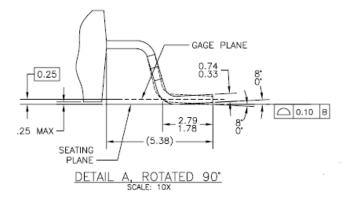




LAND PATTERN RECOMMENDATION







Dimensions in Millimeters





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